

AMENDMENTS TO THE SPECIFICATION

Please replace the paragraph at page 1, lines 5-15, with the following amended paragraph:

The present application is related to the following commonly owned U.S. Patent Applications, incorporated in their entirety herein by reference:

U.S. Patent Application No. 10/606,463 filed June 26, 2003, entitled "USE OF I²C-BASED POTENTIOMETERS TO ENABLE VOLTAGE RAIL VARIATION UNDER BMC CONTROL," naming as inventors Benjamin T. Percer, Naysen J. Robertson and Akbar Monfared (~~Attorney Docket No.: 200208051-1~~); U.S. Patent Application No. 10/606,715 filed June 26, 2003, entitled "METHODS AND SYSTEMS FOR MASKING FAULTS IN A MARGIN TESTING ENVIRONMENT" naming as inventors Benjamin T. Percer and Naysen J. Roberston (~~Attorney Docket No.: 200312936-1~~); and U.S. Patent Application No. 10/606,713 filed June 26, 2003, entitled "U.S. Patent Application No. 10/606,714 filed June 26, 2003, entitled "METHOD AND CONSTRUCT FOR ENABLING PROGRAMMABLE, INTEGRATED SYSTEM MARGIN TESTING" naming as inventors Naysen J. Robertson, Benjamin T. Percer and Sachin N. Chheda (~~Attorney Docket No.: 200207937-1~~).

Please replace the paragraph at page 1, lines 23-33, with the following amended paragraph:

Electronic systems often include a myriad of subsystems and components that require monitoring and/or testing during development, ~~manufacturing~~—and/or manufacturing while in use in the field to ensure their proper operation within specified operating conditions. Many of these components typically exhibit subtle failures at margins or extremes of such specified operating conditions. Hence, it is desirable to test the components at these margins, herein referred to as margin testing, to evaluate their reliability. For example, it may desirable to test a component by varying one or more of its operating parameters, such as, temperature, applied voltage, and/or driving frequency, over a selected range to elicit the system's response to parameter variability, especially at the extremes of specified operating conditions. Margin testing can also ensure that a particular design can be readily adapted to evolving changes in manufacturing processes.